

(Use several sheets if necessary)

Application No.:
10/530.206

Filing Date:
April 4, 2005

Group Art Unit



U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

+		Karl Wefers et al., "Oxides and Hydroxides of Aluminum", Alcoa Laboratories, pages 64-66, D1
*		Frank Henglein, "Oxidschichtbildung auf Al-Pigmenten", nanoAnalysen GmbH, Oktober 2, 2007, pages 1-6, D2
	/H.L.	Brian R. Strohmeier, "An ESCA method for determining the oxide thickness on aluminum alloys", Surface and interface analysis, 1990, vol. 15, pages 51-56, D3
*		Rolf Merz "Augerelektronenspektroskopische Untersuchung", Kaiserslautern, September 26, 2007, pages 1-14, D4
+		Ralf Belles, "Aluminum Flake Pigment", pages 785-886, B6
*		"Anwendungen von organofunktionellen elementen", Dynasol, pages 1-10, B8
		Dr. A. Schäfer, "XPS analyse von effektpigmenten", Verbaucht, August 2, 2001, pages 1-25, D10

EXAMINER:

/Hoa Le/

DATE CONSIDERED

09/20/2008

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

* Abstract provided for the Examiner's convenience

* Non-English documents without translation.

+ Undated documents.

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)		Attorney Docket No.: 0512-1269	Application No.: 10/530,206
		Applicant: Etienne DUGUET et al.	
		Filing Date: April 4, 2005	Group Art Unit:
+	Al layer thickness", nanoAnalytics, D14		
+	"Metal and effect pigment", Eckart, pages 1-3, 12-13, and 16-19, D12		
	/H.L./	G. Ertl, J. Kuppers, "Low energy electrons and surface chemistry", VCH Verlagsgesellschaft mbH, 1985, pages 54-56, D14	

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